

<b>Notice of References Cited</b>	Application/Control No. 10/840,109		Applicant(s)/Patent Under Reexamination WEEL, MARTIN	
	Examiner Le Luu		Art Unit 2454	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0113946	05-2005	Janik, Craig M.	700/094
*	B	US-2006/0218180	09-2006	Bodlaender et al.	707/103.00R
*	C	US-2004/0031058	02-2004	Reisman, Richard	725/112
*	D	US-2002/0194619	12-2002	Chang et al.	725/134
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
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	S					
	T					

#### NON-PATENT DOCUMENTS

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